

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Douglas Holtz on 10/27/2010.

The application is amended as follow:

Claim 1, line 11 after "multiple" --ultrasonic-- has been inserted,

Line 14, ", one of:" has been replaced by --a combined waveform;--, ,

Line 15-20, "a waveform comprising high negative peaks and small positive peaks, said waveform encouraging the creation of a cloud of microbubbles;

a waveform encouraging production of heat and limitation of growth and possible implosion of the microbubbles" has been deleted,

Line 21, "a combined waveform" has been changed to --wherein said combined waveform--, ,

Line 24, "only" has been deleted,

Claim 2, line 1, "A"has been changed to --The--, ,

Line 2, before "waveform" --combined-- has been inserted,

Line 2, "is one" has been changed to --comprises one--, ,

Line 4, "only" has been deleted,

Claim 3, line 2, after wherein the –combined-- has been inserted,

Line 2, “only” has been deleted,

Claim 5 line 3, after 100, “or more microns, and preferably” has been deleted,

Line 4, “between approximately 3 microns to 5 microns” has been deleted,

Claim 6, line 1, “A” has been changed to –The–,

Line 2, “wherein a control system measures” has been changed to –further comprising the step of measuring–,

Line 3, “adjusts” has been changed to –adjusting–,

Claim 7, line 1, “A” has been changed to –The–,

Lines 2-3, “a temperature control system that modifies an output of the transducers according to measured temperature” has been changed to –the step of measuring temperature of the medium and modifying an output of the transducers according to the measured temperature–,

Claim 8, line 1 “A” has been changed to –The–,

Lines 2-5, after "an ultrasound imaging or non-imaging system that views and monitors the region being targeted, monitors generation of the microbubbles at the desired location, and controls" has been changed to --the step of monitoring generation of the microbubbles at the specific location by using an ultrasound imaging or non-imaging system and controlling–,

Claim 10 line 2, after “multiple” –ultrasonic– has been inserted,

Claim 12 line 2, “different” has been replaced by --multiple ultrasonic–,

Claim 14 line 5 “, are typically at distances less than 25 mm and” has been changed to –at a distance--,

Line 6, “preferably” has been deleted,

Line 7 “and less than 10 mm” has been deleted,

Line 8 “preferably” has been deleted,

Claim 16, line 2 “array is” has been replaced by –transducers are--,

Line 4 “ultrasound” has been deleted,

Claim 18, line 13, after “vein;” –and-- has been inserted,

Claim 19, line 3 after “said” –additional-- has been inserted,

Claim 22 has been amended as follow:

22. A system ~~for carrying out the method of claim 1, said system comprising:~~ comprising:
~~at least three or more arbitrary waveform signal generators;~~
~~at least three or more wide-band power amplifiers coupled to the waveform~~
~~signal generators; wherein~~
~~three or more transducers coupled to the wide-band power amplifiers and~~
~~configured to focus ultrasound waves at a location in a medium to cause localized~~
~~production of microbubbles at said location; and~~
~~at least one workstation configured to control the production of the microbubbles~~
~~at said location, and cavitation and heating effects that take place at said location,~~
~~wherein the workstation selects a range of parameters of the ultrasound waves being~~

directed from the transducers focused at said location in order to induce cavitation, and to produce from interference of the ultrasound waves at said location:

a combined waveform comprising a spatial and/or temporal combination of two waveforms, one waveform comprising high negative peaks and small positive peaks and a second waveform comprising high positive peaks and small negative peaks, said combined waveform allowing control of size distribution of the microbubbles and temporal changes of the distribution.

Claim 23, line 2, "or more" has been deleted,

Claim 25, line 2, "or more" has been deleted,

Claim 27, line 5 ", are typically at distances less than 25 mm and" has been changed to –at a distance--,

Line 6, "preferably" has been deleted,

Line 7 "and less than 10 mm" has been deleted,

Line 8 "preferably" has been deleted,

Claim 29, line 3, "that views and monitors" has been changed to –configured to view and monitor--,

Claim 30, line 1, after wherein "the" has been replaced by –a--,

Line 2 "the" has been deleted,

Claim 32, on line 2, after measures "the" has been deleted,

Line 3 before microbubbles "the" has been deleted,

Claim 35 line 2 "is used" has been changed to –configured--,

Claim 37 line 14, "mainly" has been deleted,

2. Any inquiry concerning this communication or earlier communications from the examiner should be directed to JOEL F. BRUTUS whose telephone number is (571)270-3847. The examiner can normally be reached on Mon-Fri 7:30 AM to 5:00 PM (Off alternative Fri).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Long Le can be reached on (571)272-0823. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/J. F. B./
Examiner, Art Unit 3777

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